RELIABILITY REPORT

FOR

MAX4239Axx

PLASTIC ENCAPSULATED DEVICES

October 20, 2003

MAXIM INTEGRATED PRODUCTS

120 SAN GABRIEL DR.

SUNNYVALE, CA 94086

Written by

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Quality Assurance
Reliability Lab Manager

Reviewed by

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Quality Assurance
Executive Director

Conclusion

The MAX4239 sucessfully meets the quality and reliability standards required of all Maxim products. In addition, Maxim's continuous reliability monitoring program ensures that all outgoing product will continue to meet Maxim's quality and reliability standards.

Table of Contents

I. Device Description

A. General

The MAX4239 is a low-noise, low-drift, ultra-high precision amplifier that offers near-zero DC offset and drift through the use of patented autocorrelating zeroing technique. This method constantly measures and compensates the input offset, eliminating drift over time and temperature and the effect of 1/f noise. The device features Rail-to-Rail® outputs, operates from a single 2.7V to 5.5V supply, and consumes only 600µA. An active-low shutdown mode decreases supply current to 0.1µA.

The decompensated MAX4239 is stable with AV $\geq$ 10V/V and a GBWP of 6.5MHz. The MAX4239 is available in 8-pin narrow SO and 6-pin SOT23 packages.

B. Absolute Maximum Ratings

Item	Rating
Power-Supply Voltage (VCC to GND)	6V
All Other Pins	(GND - 0.3V) to (VCC + 0.3V)
Output Short-Circuit Duration (OUT shorted to VCC or GND)	Continuous
Operating Temperature Range	-40°C to +125°C
Junction Temperature	+150°C
Storage Temperature Range	-65°C to +150°C
Lead Temperature (soldering, 10s)	+300°C
Continuous Power Dissipation (TA = +70°C)	
6-Pin SOT23	727mW
8-Pin SO	471mW
Derates above +70°C	
6-Pin SOT23	9.1mW/°C
8-Pin SO	5.88mW/°C

II. Manufacturing Information

A. Description/Function:	Ultra-Low Offset/Drift, Low-Noise, Precision SOT23 Amplifiers
B. Process:	B8 (Standard 0.8 micron silicon gate CMOS)
C. Number of Device Transistors:	821
D. Fabrication Location:	California, USA
E. Assembly Location:	Philippines, Malaysia or Thailand
F. Date of Initial Production:	July, 2002

III. Packaging Information

A. Package Type:	**8-Lead SO**	**6-Lead SOT23 Flip-Chip**
B. Lead Frame:	Copper	Copper
C. Lead Finish:	Solder Plate	Solder Plate
D. Die Attach:	Silver-Filled Epoxy	N/A
E. Bondwire:	Gold (1.0 mil dia.)	6 mil dia. ball
F. Mold Material:	Epoxy with silica filler	Epoxy with silica filler
G. Assembly Diagram:	# 05-2501-0192	# 05-2501-0191
H. Flammability Rating:	Class UL94-V0	Class UL94-V0
I. Classification of Moisture Sensitivity per JEDEC standard JESD22-A112:	Level 1	Level 1

IV. Die Information

A. Dimensions:	90 x 45 mils
B. Passivation:	Si_3N_4/SiO_2 (Silicon nitride/ Silicon dioxide)
C. Interconnect:	Aluminum/Copper/Silicon
D. Backside Metallization:	None
E. Minimum Metal Width:	.8 microns (as drawn)
F. Minimum Metal Spacing:	.8 microns (as drawn)
G. Bondpad Dimensions:	5 mil. Sq.
H. Isolation Dielectric:	SiO_2
I. Die Separation Method:	Wafer Saw

V. Quality Assurance Information

A. Quality Assurance Contacts:

Jim Pedicord	(Manager, Reliability Operations)
Bryan Preeshl	(Executive Director of QA)
Kenneth Huening	(Vice President)

B. Outgoing Inspection Level: 0.1% for all electrical parameters guaranteed by the Datasheet.
0.1% For all Visual Defects.

C. Observed Outgoing Defect Rate: < 50 ppm

D. Sampling Plan: Mil-Std-105D

VI. Reliability Evaluation

A. Accelerated Life Test

The results of the 135°C biased (static) life test are shown in **Table 1**. Using these results, the Failure Rate (λ) is calculated as follows:

$$\lambda = \frac{1}{MTTF} = \frac{1.83}{192 \times 4389 \times 80 \times 2}$$

(Chi square value for MTTF upper limit)

Thermal acceleration factor assuming a 0.8eV activation energy

$\lambda = 13.57 \times 10^{-9}$ $\lambda = 13.57$ F.I.T. (60% confidence level @ 25°C)

This low failure rate represents data collected from Maxim's reliability qualification and monitor programs. Maxim also performs weekly Burn-In on samples from production to assure the reliability of its processes. The reliability required for lots which receive a burn-in qualification is 59 F.I.T. at a 60% confidence level, which equates to 3 failures in an 80 piece sample. Maxim performs failure analysis on lots exceeding this level. The following Burn-In Schematic (Spec. #06-5803) shows the static circuit used for this test. Maxim also performs 1000 hour life test monitors quarterly for each process. This data is published in the Product Reliability Report (**RR-1M**).

B. Moisture Resistance Tests

Maxim evaluates pressure pot stress from every assembly process during qualification of each new design. Pressure Pot testing must pass a 20% LTPD for acceptance. Additionally, industry standard 85°C/85%RH or HAST tests are performed quarterly per device/package family.

C. E.S.D. and Latch-Up Testing

The OX60-1 die type has been found to have all pins able to withstand a transient pulse of +/-2500V, per Mil-Std-883 Method 3015 (reference attached ESD Test Circuit). Latch-Up testing has shown that this device withstands a current of ±250mA.

Table 1
Reliability Evaluation Test Results

MAX4239Axx

TEST ITEM	TEST CONDITION	FAILURE IDENTIFICATION	PACKAGE	SAMPLE SIZE	NUMBER OF FAILURES
Static Life Test (Note 1)					
	Ta = 135°C Biased Time = 192 hrs.	DC Parameters & functionality		80	0
Moisture Testing (Note 2)					
Pressure Pot	Ta = 121°C P = 15 psi. RH= 100% Time = 168hrs.	DC Parameters & functionality	SO SC70	77 77	0 0
85/85	Ta = 85°C RH = 85% Biased Time = 1000hrs.	DC Parameters & functionality		77	0
Mechanical Stress (Note 2)					
Temperature Cycle	-65°C/150°C 1000 Cycles Method 1010	DC Parameters & functionality		77	0

Note 1: Life Test Data may represent plastic DIP qualification lots.
Note 2: Generic Package/Process data

Attachment #1

TABLE II. Pin combination to be tested. 1/ 2/

	Terminal A (Each pin individually connected to terminal A with the other floating)	Terminal B (The common combination of all like-named pins connected to terminal B)
1.	All pins except V_{PS1} 3/	All V_{PS1} pins
2.	All input and output pins	All other input-output pins

1/ Table II is restated in narrative form in 3.4 below.
2/ No connects are not to be tested.
3/ Repeat pin combination I for each named Power supply and for ground

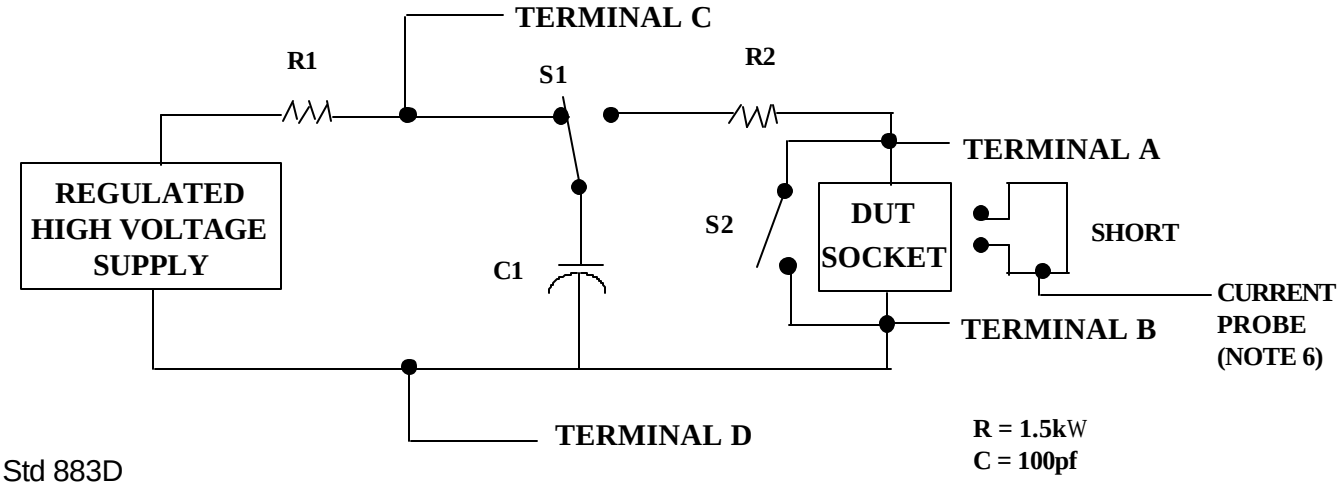
(e.g., where V_{PS1} is V_{DD}, V_{CC}, V_{SS}, V_{BB}, GND, $+V_S$, $-V_S$, V_{REF}, etc).

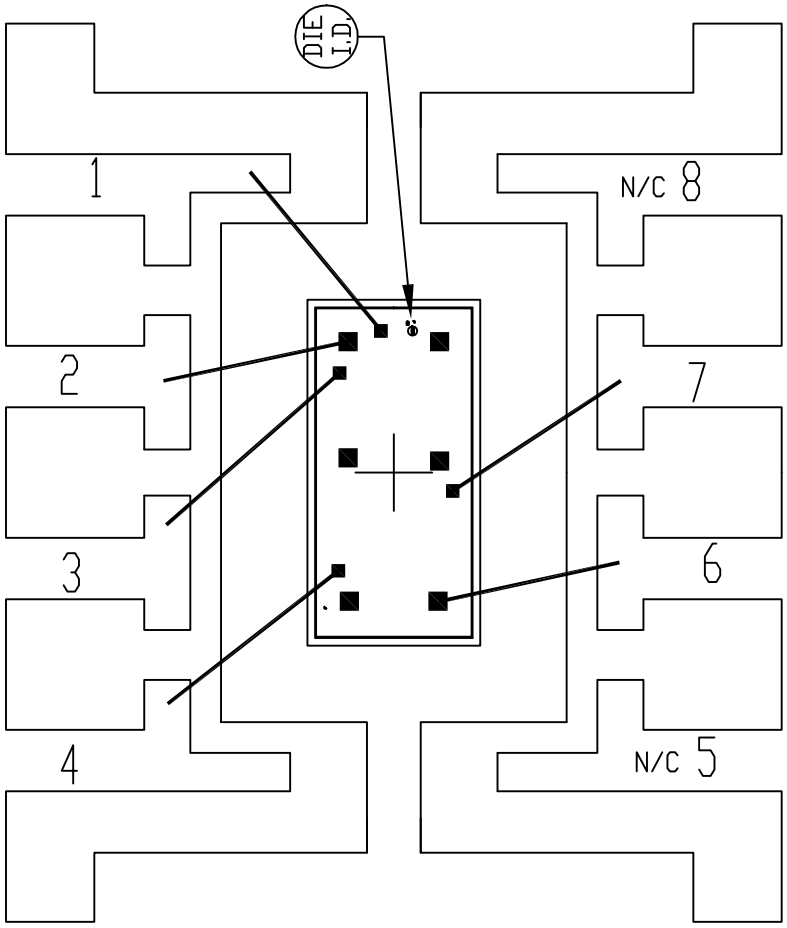
3.4 Pin combinations to be tested.

a. Each pin individually connected to terminal A with respect to the device ground pin(s) connected to terminal B. All pins except the one being tested and the ground pin(s) shall be open.

b. Each pin individually connected to terminal A with respect to each different set of a combination of all named power supply pins (e.g., V_{SS1}, or V_{SS2} or V_{SS3} or V_{CC1}, or V_{CC2}) connected to terminal B. All pins except the one being tested and the power supply pin or set of pins shall be open.

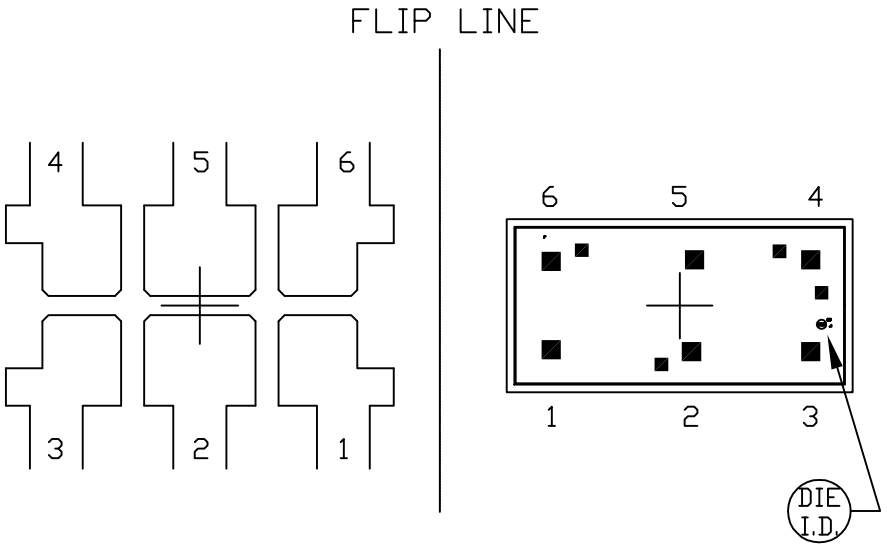
c. Each input and each output individually connected to terminal A with respect to a combination of all the other input and output pins connected to terminal B. All pins except the input or output pin being tested and the combination of all the other input and output pins shall be open.





PKG. CODE: S8-4		SIGNATURES	DATE	MAXIM CONFIDENTIAL & PROPRIETARY	
CAV./PAD SIZE: 90 X 130	PKG.	RAMON DE LEON	11/7/01	BOND DIAGRAM #: 05-2501-0192	REV: B
	DESIGN	F. FONDERIE	11/8/01		

FLIP CHIP PKG.



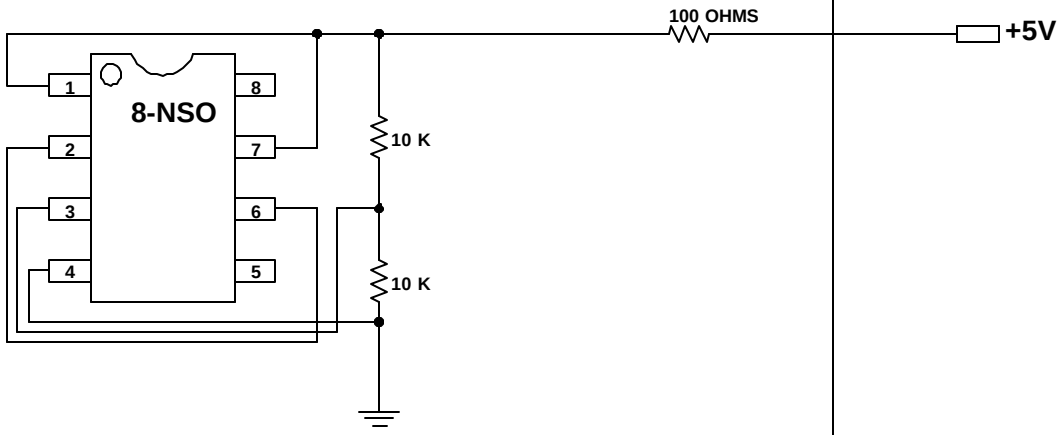
ORIGINAL PINOUTS

NOTE: CAVITY DOWN

PKG. CODE: U6F-6		SIGNATURES	DATE	MAXIM CONFIDENTIAL & PROPRIETARY	
CAV./PAD SIZE: FLIP CHIP	PKG.	HUNT JIANG	11/8/01	BOND DIAGRAM #: 05-2501-0191	REV: B
	DESIGN	J. FONDERIE	11/8/01		

ONCE PER SOCKET

ONCE PER BOARD



DEVICES: MAX 4238

MAX. EXPECTED CURRENT = 1.2mA

DRAWN BY: HAK TAN

NOTES: